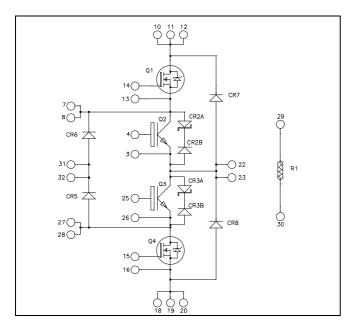


Three level inverter CoolMOS & Trench + Field Stop IGBT3 Power Module

Trench & Field Stop IGBT3 Q2, Q3: $V_{CES} = 600V$; $I_C = 75A$ @ $Tc = 80^{\circ}C$

CoolMOSTM Q1, Q4:

 $V_{DSS} = 600V$; $I_D = 70A$ @ Tc = 80°C



Application

- Solar converter
- Uninterruptible Power Supplies

Features

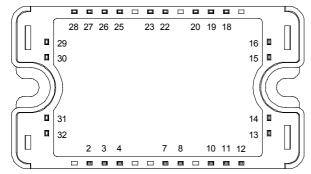
- Q2, Q3 Trench + Field Stop IGBT3 Technology
 - Low voltage drop
 - Low tail current
 - Switching frequency up to 20 kHz
 - Soft recovery parallel diodes
 - Low diode VF
 - Low leakage current
 - RBSOA and SCSOA rated

• Q1, Q4 CoolMOSTM

- Ultra low R_{DSon}
- Low Miller capacitance
- Ultra low gate charge
- Avalanche energy rated
- Very rugged
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring

Benefits

- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive TC of VCEsat
- Low profile
- RoHS Compliant



All multiple inputs and outputs must be shorted together Example: 10/11/12; 7/8 ...

All ratings @ $T_i = 25$ °C unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com

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Q1 & Q4 Absolute maximum ratings (per CoolMOSTM)

Symbol	Parameter		Max ratings	Unit		
$V_{ m DSS}$	Drain - Source Breakdown Voltage		600	V		
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	95			
I_{D}	Continuous Diani Current	$T_c = 80$ °C	70	Α		
I_{DM}	Pulsed Drain current		260			
V_{GS}	Gate - Source Voltage	±20	V			
R _{DSon}	Drain - Source ON Resistance		24	mΩ		
P_{D}	Maximum Power Dissipation	$T_c = 25$ °C	462	W		
I_{AR}	Avalanche current (repetitive and non repetitive)		15	A		
E _{AR}	Repetitive Avalanche Energy		3	mJ		
E_{AS}	Single Pulse Avalanche Energy		1900	1113		

Q1 & Q4 Electrical Characteristics (per CoolMOSTM)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
Ţ	Zara Cata Valtaga Drain Current	$V_{GS} = 0V, V_{DS} = 600V$	$T_j = 25^{\circ}C$			350	^
$I_{ m DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 600V$	$T_j = 125$ °C			600	μΑ
R _{DS(on)}	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 47.5A$				24	mΩ
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 5mA$		2.1	3	3.9	V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$				200	nA

Q1 & Q4 Dynamic Characteristics (per CoolMOSTM)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V ; V_{DS} = 25V$		14.4		nF
C_{oss}	Output Capacitance	f=1MHz		17		111
Q_{g}	Total gate Charge	$V_{GS} = 10V$		300		
Q_{gs}	Gate – Source Charge	$V_{Bus} = 300V$ $I_D = 95A$		68		nC
Q_{gd}	Gate – Drain Charge			102		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (125°C) $V_{GS} = 10V$		21		
T_{r}	Rise Time			30		ns
$T_{d(off)}$	Turn-off Delay Time	$V_{\text{Bus}} = 400V$ $I_{\text{D}} = 95A$		100		
T_{f}	Fall Time	$R_G = 2.5\Omega$		45		
Eon	Turn-on Switching Energy	Inductive switching @ 25°C		1350		μJ
E _{off}	Turn-off Switching Energy	$V_{GS} = 10V ; V_{Bus} = 400V$ $I_D = 95A ; R_G = 2.5\Omega$		1040		μι
Eon	Turn-on Switching Energy	Inductive switching @ 125°C		2200		I
E_{off}	Turn-off Switching Energy	$V_{GS} = 10V ; V_{Bus} = 400V$ $I_D = 95A ; R_G = 2.5\Omega$		1270		μJ
R_{thJC}	Junction to Case Thermal Resistance				0.27	°C/W

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Q2 & Q3 Absolute maximum ratings (per IGBT)

Symbol	Parameter		Max ratings	Unit
V_{CES}	Collector - Emitter Breakdown Voltage		600	V
T.	Continuous Collector Current	$T_C = 25^{\circ}C$	100	
I _C Continuous Collecto	Continuous Concetor Current	$T_C = 80$ °C	75	Α
I_{CM}	Pulsed Collector Current	$T_C = 25^{\circ}C$	140	
V_{GE}	Gate – Emitter Voltage		±20	V
P_{D}	Maximum Power Dissipation	$T_C = 25$ °C	250	W
RBSOA	Reverse Bias Safe Operating Area	$T_J = 150$ °C	150A @ 550V	

Q2 & Q3 Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
I_{CES}	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} = 600V$				250	μΑ
V _{CE(sat)}	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25$ °C		1.5	1.9	V
V CE(sat)		$I_C = 75A$	$T_{j} = 150^{\circ}C$		1.7		v
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 600 \mu A$		5.0	5.8	6.5	V
I_{GES}	Gate – Emitter Leakage Current	$V_{GE} = 20V$, $V_{CE} = 0V$				600	nA

Q2 & Q3 Dynamic Characteristics (per IGBT)

	Characteristic	Test Conditions	;	Min	Typ	Max	Unit
C_{ies}	Input Capacitance	$V_{GE} = 0V$			4620		
C_{oes}	Output Capacitance	$V_{CE} = 25V$			300		pF
C_{res}	Reverse Transfer Capacitance	f = 1MHz			140		
Q_{G}	Gate charge	V_{GE} =±15V, I_{C} =75A V_{CE} =300V			0.8		μС
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (25°C)			110		
$T_{\rm r}$	Rise Time	$V_{GE} = \pm 15V$			45		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 300V$ $I_C = 75A$			200		ns
$T_{\rm f}$	Fall Time	$R_G = 4.7\Omega$	C		40		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch $V_{GE} = \pm 15V$	hing (150°C)		120		
T_{r}	Rise Time	$V_{\text{Bus}} = 300V$			50		ns
$T_{d(off)}$	Turn-off Delay Time	$I_C = 75A$			250		
$T_{\rm f}$	Fall Time	$R_G = 4.7\Omega$			60		
Eon	Turn-on Switching Energy	$V_{GE} = \pm 15V$	$T_j = 25^{\circ}C$		0.35		mJ
Lon	Turn on Switching Energy	$V_{\text{Bus}} = 300V$	$T_{j} = 150^{\circ}C$		0.6		1113
E_{off}	Turn-off Switching Energy	$I_{\rm C} = 75A$	$T_j = 25^{\circ}C$		2.2		mJ
2 0∏	Tain on Switching Energy	$R_G = 4.7\Omega$	$T_{j} = 150^{\circ}C$		2.6		1110
I_{sc}	Short Circuit data	$V_{GE} \le 15V ; V_{Bu}$ $t_p \le 6\mu s ; T_i = 15$			380		A
R_{thJC}	Junction to Case Thermal Resistance					0.60	°C/W



CR2 & CR3 diode ratings and characteristics (per device)

_	Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
	$V_{\rm F}$	Diode + tranzorb Forward Voltage	$I_F = 10A$		10		V
I	R_{thJC}	Junction to Case Thermal Resistance				8	°C/W

CR5 & CR6 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			600			V
I_{RM}	Maximum Reverse Leakage Current	$V_R=600V$				25	μA
I_F	DC Forward Current		$Tc = 80^{\circ}C$		30		Α
		$I_F = 30A$			1.8	2.2	
V_{F}	Diode Forward Voltage	$I_F = 60A$			2.2		V
		$I_F = 30A$	$T_i = 125$ °C		1.5		
t	t_{rr} Reverse Recovery Time $I_F = 30A$		$T_j = 25$ °C		25		ns
r _{rr}		$I_F = 30A$ $V_R = 400V$	$T_{j} = 125^{\circ}C$		160		113
Q_{rr}	Reverse Recovery Charge	$di/dt = 200 A/\mu s$	$T_j = 25$ °C		35		nC
Qrr	Reverse Recovery Charge	·	$T_{j} = 125^{\circ}C$		480		iic
E_{rr}	Reverse Recovery Energy	$\begin{split} I_F &= 30A \\ V_R &= 400V \\ di/dt &= 1000A/\mu s \end{split}$	$T_j = 125$ °C		0.6		mJ
R_{thJC}	Junction to Case Thermal Resistance					1.2	°C/W

CR7 & CR8 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			1200			V
I_{RM}	Maximum Reverse Leakage Current	$V_R = 1200V$				100	μΑ
I_{F}	DC Forward Current		$Tc = 80^{\circ}C$		30		Α
		$I_F = 30A$			2.6	3.1	
V_{F}	Diode Forward Voltage	$I_F = 60A$			3.2		V
		$I_F = 30A$	$T_{i} = 125^{\circ}C$		1.8		
t _{rr}	Reverse Recovery Time		$T_j = 25^{\circ}C$		300		ns
ι _{rr}		$I_F = 30A$ $V_R = 800V$	$T_j = 125$ °C		380		115
Q_{rr}	Reverse Recovery Charge	$di/dt = 200 \text{ A/}\mu\text{s}$	$T_j = 25^{\circ}C$		360		пC
Qrr	Reverse Recovery Charge		$T_{j} = 125^{\circ}C$		1700		IIC
E_{rr}	Reverse Recovery Energy	$I_F = 30A$ $V_R = 800V$ $di/dt = 1000A/\mu s$	$T_j = 125$ °C		1.6		mJ
R_{thJC}	Junction to Case Thermal Resistance		•			1.2	°C/W



Temperature sensor NTC (see application note APT0406 on www.microsemi.com for more information).

Symbol	Characteristic			Тур	Max	Unit
R ₂₅	Resistance @ 25°C	sistance @ 25°C		50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B _{25/85}	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta \mathrm{B/B}$		T _C =100°C		4		%

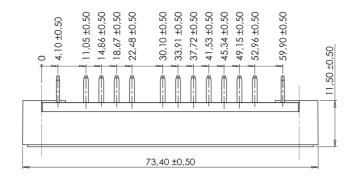
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature R_T: Thermistor value at T

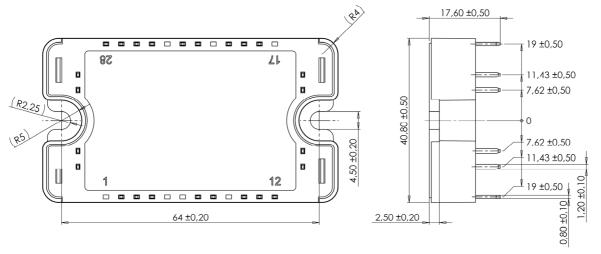
Thermal and package characteristics

Symbol	Characteristic		Min	Тур	Max	Unit	
V_{ISOL}	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000			V
T_{J}	Operating junction temperature range		-40		175*		
T_{STG}	Storage Temperature Range			-40		125	°C
$T_{\rm C}$	Operating Case Temperature			-40		100	
Torque	Mounting torque	To heatsink	M4	2		3	N.m
Wt	Package Weight					110	g

^{*} Tjmax = 150°C for Q1 & Q4

SP3 Package outline (dimensions in mm)



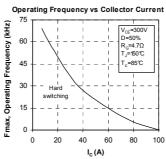


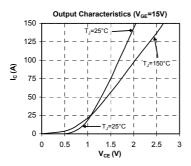
See application note 1901 - Mounting Instructions for SP3 Power Modules on www.microsemi.com

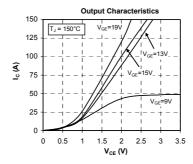
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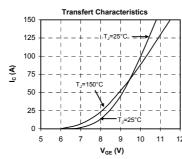


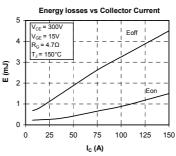
Q2 & Q3 Typical performance curve

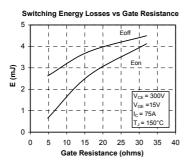


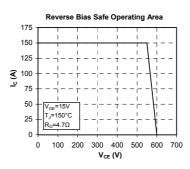


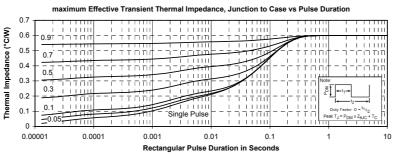








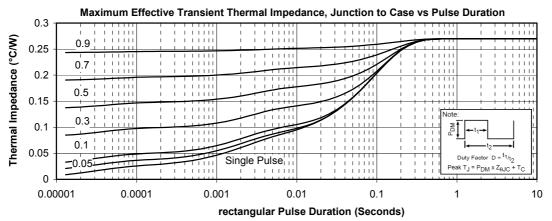


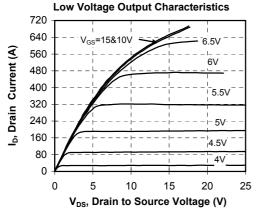


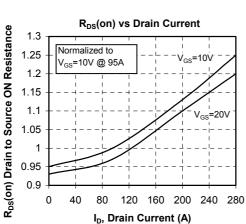
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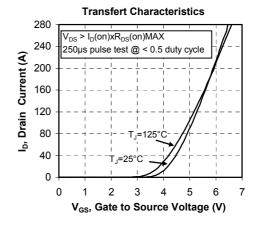


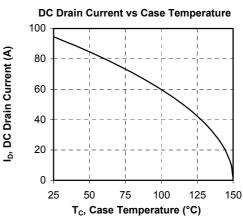
Q1 & Q4 Typical performance curve



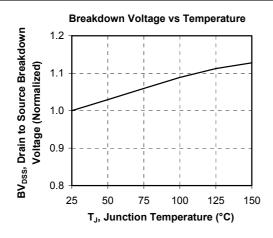


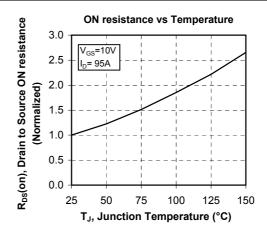


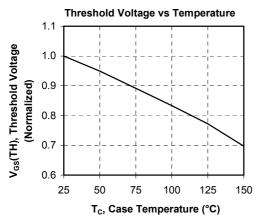


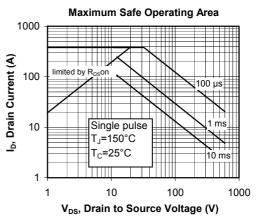


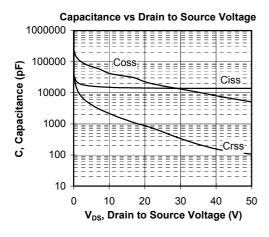


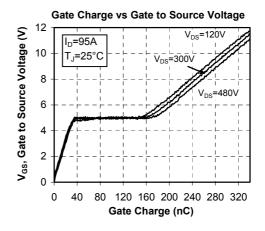




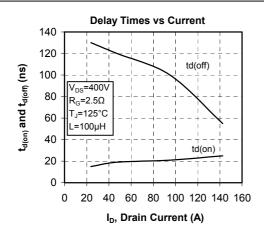


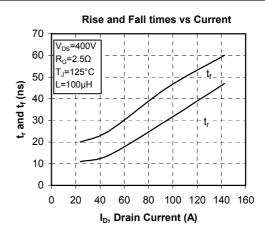


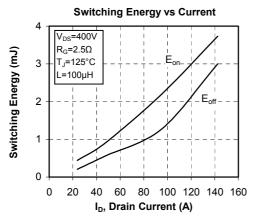


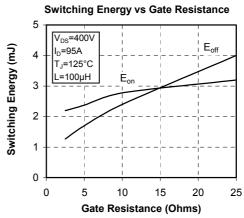


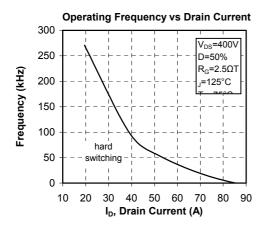


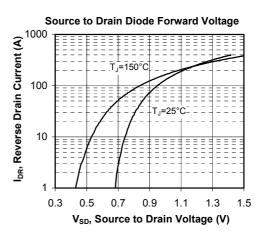






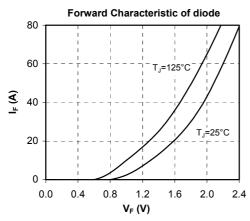


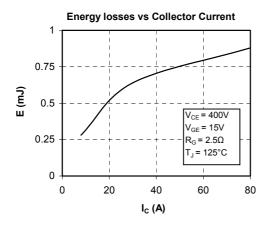


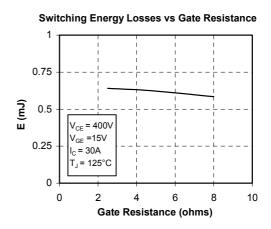


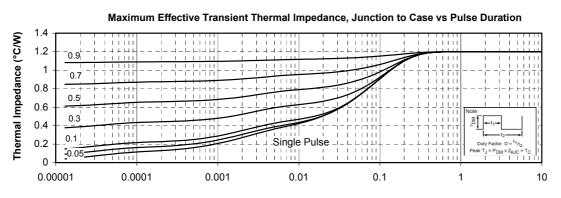


CR5 & CR6 Typical performance curve





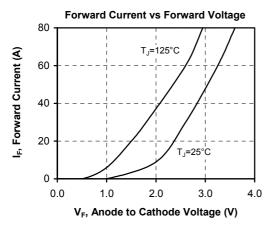




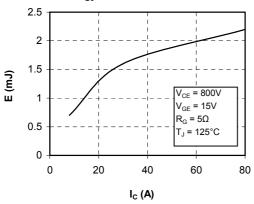
Rectangular Pulse Duration (Seconds)



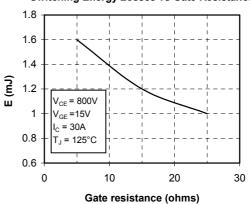
CR7 & CR8 Typical performance curve



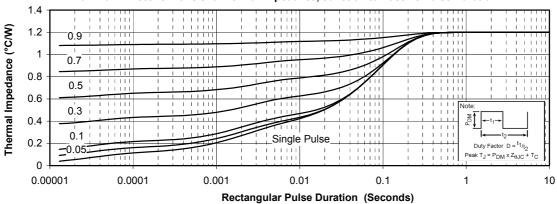
Energy losses vs Collector Current



Switching Energy Losses vs Gate Resistance



Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration



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